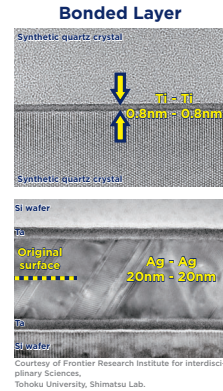
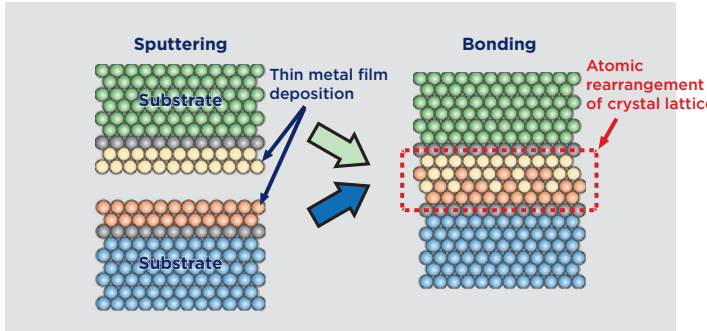


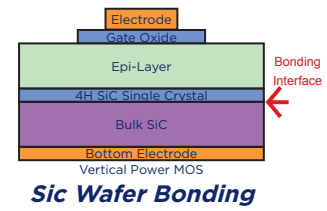
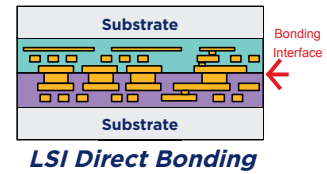
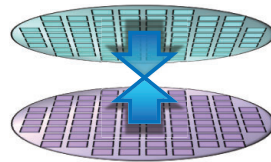
# 3D Integration

## Atomic Diffusion Bonding Technology



✓ Almost any metal can be used as bonding layer!

**SiC + SiC  
Piezoelectric + Si  
3D Integration**



**NEW!**



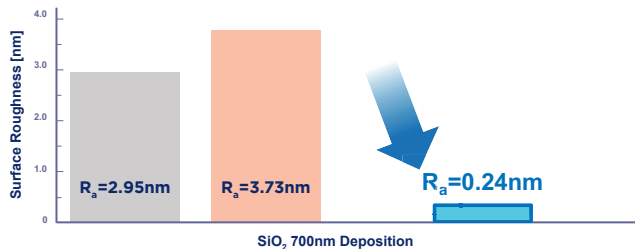
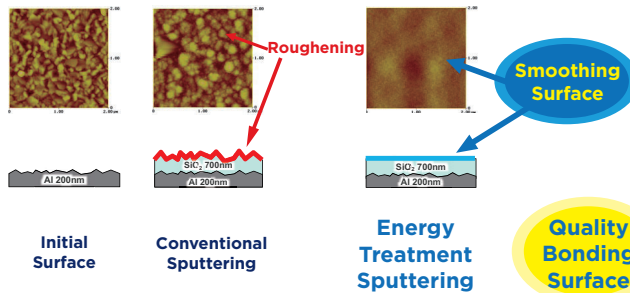
**Development Road Map**

	2019	2020	2021	2022
Substrate Size	Φ100mm, Φ150mm (Available now)			
	Φ200mm, Φ300mm			
Alignment Accuracy	< 0.15mm		Hybrid Bonding 3D Integration	
			< 1.0μm	
			< 0.1μm	

## Bonding Capable Smooth Surface

✓ To Make Roughening Surface Flat by Deposition

**NEW!**



**EC7420 Energy Treatment Sputtering Equipment**

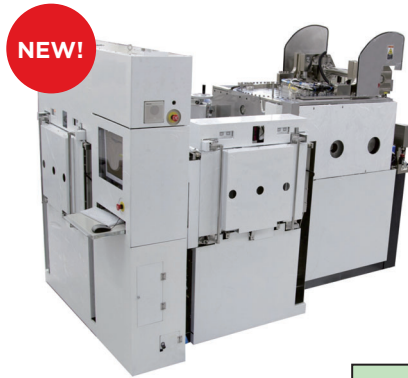
**Specifications**

Planetary Substrate Holder	Φ4" 5 wafers/batch Φ6" 4 wafers/batch
Deposition Uniformity	WIW $\pm 1\%$ <sup>1</sup>
Deposition Rate	>30 nm/min *2

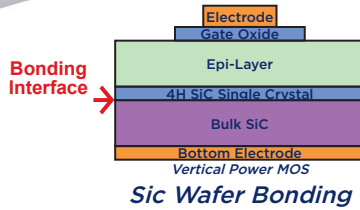
<sup>1</sup> Φ4" Si wafer  
<sup>2</sup> Smoothing surface process

# Power Device Solution

## SiC Wafer Bonding



### BC7000 Atomic Diffusion Bonding Equipment

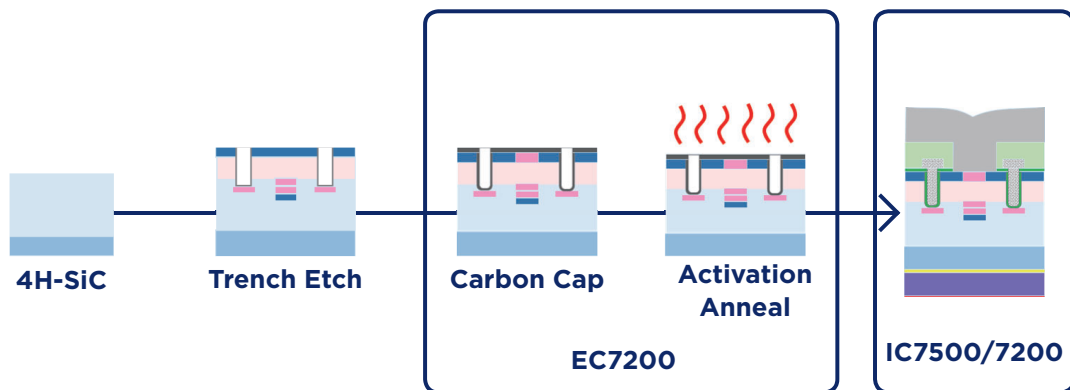


Specifications	
Base Pressure	$5 \times 10^{-7}$ Pa
Deposition Uniformity*1	WIW < $\pm 2\%$ WTW < $\pm 1.5\%$
Particles	$0.3-0.5\mu\text{m} \leq 20$ $0.5-1.0\mu\text{m} \leq 10$ $1.0\mu\text{m} \sim \leq 10$
Alignment Accuracy ( $3\sigma$ )	XY < $\pm 0.3\text{mm}$ $\theta < \pm 0.3^\circ$
Throughput	$\geq 17\text{wph}$

\*1 Measurement points : 6" wafer EE10mm



## SiC Trench MOSFET Process



### EC7200 SiC Carbon Cap and Activation Anneal

The Surface Roughness	
Initial	1800°C/5min
RMS=0.16nm	RMS=0.19nm
-	AR <sup>*</sup> =100%

\*AR: Activation Ratio  
(Al implant:  $7E^{13}/\text{cm}^2$ )



### IC7500/7200 Sputtering Process for SiC Device

Metallization Materials	
p/n-Contact Metal	Al, Ti, Ni
Back Surface Contact Metal	Ti, Ni
Interconnect	Ti, Al
Back Side Electrode	Ti, Ni, Au
Pad Electrode	Ti, Ni, Au
Schottky Electrode	Ti, Mo

Extremely flat surface and perfect activation